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transient current testing power supply

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## Patents

Patents 1 - 20 on **transient current testing power supply**. (0.54 seconds)

## › List view

[Cover view](#)Integrated circuit test **power supply**

US Pat. 5773990 - Filed Sep 29, 1995 - Megatest Corporation

One embodiment of a **power supply for testing** an integrated circuit includes a source ... This minimizes VDD changes when the DUT demands **transient current**,

...

## › Sort by relevance

[Sort by date \(new first\)](#)[Sort by date \(old first\)](#)Arrangement for **transient-current testing** of a digital electronic CMOS circuit

US Pat. 6414511 - Filed Feb 7, 2000 - Koninklijke Philips Electronics N.V.

Generally, **transient-current** measurements or so-called IDDT ... 38 that has an importantly unsymmetric **power supply** at +30 and -5 volts, respectively, ...

## › Any status

[Issued patents](#)[Applications](#)Apparatus for reducing **power supply** noise in an integrated circuit

US Pat. 6339338 - Filed Jan 18, 2000 - Formfactor, Inc.

An apparatus for limiting variation in **power supply** voltage at a **power** input ... in voltage results from a **transient current** the IC draws at its **power** input ...

Apparatus and method for defect **testing** of integrated circuits

US Pat. 6031386 - Filed Oct 31, 1997 - Sandia Corporation

DDQ **testing** is based on the principle that CMOS ICs are designed to provide a very small quiescent **power supply current** drain due to leakage that is on the

...

Method and apparatus for performing operative **testing** on an integrated circuit

US Pat. 5929650 - Filed Feb 4, 1997 - Motorola, Inc.

As seen in the prior art, quiescent **current testing** is efficient in CMOS digital circuits ... of the **power supply** line of the device, Vdd. Referring to FIG. ...

Fast recovery power supply

US Pat. 4686462 - Filed Sep 26, 1985 - International Business Machines Corporation

Because capacitor 35 now recharges quickly the said **transient current** and quickly ... Thus, fast recovery **power supply**, the output 37 provides a measurable ...

System level latchup mitigation for single event and transient radiation ...

US Pat. 5672918 - Filed Aug 18, 1994 - The United States of America as represented by the United States Department of Energy

7D shows a typical **power supply** voltage. An arbitrary **power** dump period of 5 ... and **transient current** measurements were made on the +28 and +5 **power** buses ...

Apparatus and method for testing electrically controlled motor

US Pat. 4996477 - Filed Oct 26, 1989 - A.O. Smith Corporation

The portable test unit of claim 2, having a **power** lamp and a parallel **transient current** capacitor, switch connecting said test **power supply** to said selec- ...

Dynamic burn-in test equipment

US Pat. 6215324 - Filed Jan 5, 2000 - Nippon Scientific Co., Ltd.

For this reason, **current** detectors of the present invention are preferably inserted into both a higher level **power supply** line side and a lower level **power**

...

Integrated circuit fault testing implementing voltage supply rail pulsing ...

US Pat. 5483170 - Filed Aug 24, 1993 - New Mexico State University Technology Transfer Corp.

The pre-bias voltage will cause the **power supply** rails of the circuit to be tested to ... A simple **current** mirror detected the **transient current** (IDD) while

...

Voltage generating circuit for IC test

US Pat. 5594359 - Filed Jun 2, 1995 - Advantest Corporation

A voltage generating circuit for **testing** an IC device, comprising: 5 an ... amplifier and said **power supply** terminal for detecting a **current** flowing to said

...

Probe interface assembly

US Pat. 5144228 - Filed Apr 23, 1991 - International Business Machines Corporation

9, the capacitor 164 may be viewed 40 alternately as a **supply** of energy to provide **power** surges as required for **transient current** flow, or as a decoupling ...

### Quiescent **current** monitor circuit for wafer level integrated circuit **testing**

US Pat. 5912562 - Filed Feb 4, 1997 - Motorola Inc.

As seen in the prior art, quiescent **current testing** is efficient in CMOS ... of the parasitic capacitance of the **power supply** line of the device, VDD. ...

### Built-in **current testing** of integrated circuits

US Pat. 5025344 - Filed Feb 22, 1990 - Carnegie Mellon University

the comparator to disconnect **power** to the tested module when the quiescent ... and appears only during **transient current** peaks as an extra voltage drop ...

### Rapid transit system **transient** voltage suppression apparatus

US Pat. 4322772 - Filed Mar 21, 1980 - Westinghouse Electric Corp.

5, and assuming a **power supply** having a maximum rated voltage of 720 volts and a **transient fault current** to be suppressed of 5000 amperes as shown by FIG. ...

### Voltage sag/swell **testing** station

US Pat. 5886429 - Filed Dec 11, 1997 - Board of Regents, The University of Texas System

... 32 for **transient current** protection purposes. A master on-off control or bypass switch 50 is electrically connected by conductor 52 to the **power supply** ...

### Method for fabricating integrated circuit (IC) dies with multi-layered ...

US Pat. 6423558 - Filed Feb 25, 2000 - Adventest Corporation

The quiescent **power supply current** test is a procedure which assumes a ... " Defect Detection with **Transient Current Testing** 35 and its Potential for Deep ...

### Built-in test circuit for static CMOS circuits

US Pat. 5097206 - Filed Oct 5, 1990 - Hewlett-Packard Company

Low 36 is low and pass transistors 16 and 60 are conducting, **current** transistor 48 is ... If multiple **power** busses are required, the **Transient** behavior of ...

### Clamp circuit to prevent ESD damage to an integrated circuit

US Pat. 6400540 - Filed Mar 11, 2000 - Silable Inc.

As the ESD event is a fast **transient** event, the peak ESD event **current** flowing

... In normal operation the **power supply** potential is greater than the ground

...

Quiescent **power supply current** test method and apparatus for integrated ...

US Pat. 5731700 - Filed Jun 19, 1996 - LSI Logic Corporation

1 2 QUIESCENT **POWER SUPPLY CURRENT** The output of the **current** sensor 12 is ... of

Field Effect Transistors (FET) that are arranged to con- high **transient** ...

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## Patents

Patents 1 - 20 on transient current testing power supply fault. (0.08 seconds)

## › List view

[Cover view](#)Integrated circuit **fault testing** implementing voltage **supply** rail pulsing ...

US Pat. 5483170 - Filed Aug 24, 1993 - New Mexico State University Technology Transfer Corp.

The pre-bias voltage will cause the **power supply** rails of the circuit to be tested to ... A simple **current** mirror detected the **transient current** (IDD) while

...

## › Sort by relevance

[Sort by date \(new first\)](#)[Sort by date \(old first\)](#)Fast recovery **power supply**

US Pat. 4686462 - Filed Sep 26, 1985 - International Business Machines Corporation

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Generally, **transient-current** measurements or so-called IDDT ... 38 that has an importantly unsymmetric **power supply** at +30 and -5 volts, respectively, ...

Method for fabricating integrated circuit (IC) dies with multi-layered ...

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

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US Pat. 5025344 - Filed Feb 22, 1990 - Carnegie Mellon University

the comparator to disconnect **power** to the tested module when the quiescent ... and appears only during **transient current** peaks as an extra voltage drop ...

Rapid transit system **transient** voltage suppression apparatus

US Pat. 4322772 - Filed Mar 21, 1980 - Westinghouse Electric Corp.

5, and assuming a **power supply** having a maximum rated voltage of 720 volts and a **transient fault current** to be suppressed of 5000 amperes as shown by FIG. ...

Quiescent **current testing** of dynamic logic systems

US Pat. 5557620 - Filed Sep 25, 1995 - Hewlett-Packard Company

**Testing** based on detecting an increase in **power supply current** is called quiescent ... **current mea-** 60 surement must be performed at a time when **transient ...**

Automatic controlled for an ice and snow melting system with ground **fault ...**

US Pat. 5710408 - Filed Aug 15, 1996 - MSX, Inc.

The heater 14 **supply** leads are 35 Operating the switch 98 causes the test ...That is, unless a ground **fault current** the one-turn primary windings 74 and 76

...

Method and apparatus for performing operative **testing** on an integrated circuit

US Pat. 5929650 - Filed Feb 4, 1997 - Motorola, Inc.

As seen in the prior art, quiescent **current testing** is efficient in CMOS digital circuits ... of the **power supply** line of the device, Vdd. Referring to FIG. ...

Built-in test circuit for static CMOS circuits

US Pat. 5097206 - Filed Oct 5, 1990 - Hewlett-Packard Company

During the test mode, row **power** buss 18 is in ing state, the **current ...** the gates to switch states demands **transient current** pass transistor 28 in any ...

Integrated circuit **fault testing** system based on **power** spectrum analysis of ...

US Pat. 5949798 - Filed Feb 4, 1997 - NEC Corporation

1 2 INTEGRATED CIRCUIT **FAULT TESTING** transistor switching **current** in a CMOS ... there is **current** flows as the **supply current** except for **transient** 1S ...

Elevated voltage level I.sub.DDQ failure **testing** of integrated circuits

US Pat. 5519333 - Filed Sep 9, 1994 - Sandia Corporation

The **power supply** voltage level of the device must be the same level as 50 the logic level "1" for ... is an 60 arbitrary acronym for this **transient current**

...

Circuit breaker incorporating **fault** lockout protection

US Pat. 6657837 - Filed Dec 29, 1999 - General Electric Company

Electronic trip unit 51 senses **current** in **supply** line 104, ... thus eliminating the switching **transient current** on contact bypass lines 152, 154, 156. ...

Method and apparatus for **testing** an AFCI/GFCI circuit breaker

US Pat. 6426632 - Filed Apr 28, 2000 - George A. Spencer

A related technology developed to disable a **power** circuit in the event of a ground **fault** — typically an unintended leakage **current** path between a live ...

Device for preventive detection of faults with recognition of the type of load

US Pat. 5910875 - Filed Aug 5, 1997 - Schneider Electric SA

It then performs **fault** detection by measuring the **current** in the load when ...  
the **current** when the test **power supply** is constituted by a pulse generator. ...

Device for preventive detection of faults with identification of the type of ...

US Pat. 6081123 - Filed Oct 24, 1997 - Schneider Electric SA

It then performs **fault** detection by measuring the **current** in the load when ...  
the **current** when the test **power supply** is constituted by a pulse generator. ...

Redundant **power supply** and storage system

US Pat. 5747889 - Filed Jul 31, 1996 - Hewlett-Packard Company

5, a **power supply fault** indicates that the **current** sharing. ... adjusted for  
opti- Recovery of the **power supply** at issue is achieved by the mum **transient** ...

Quiescent **current** monitor circuit for wafer level integrated circuit **testing**

US Pat. 5912562 - Filed Feb 4, 1997 - Motorola Inc.

As seen in the prior art, quiescent **current testing** is efficient in CMOS ... of  
the parasitic capacitance of the **power supply** line of the device, VDD. ...

Semiconductor integrated circuit **fault** analyzing apparatus and method therefor

US Pat. 5521516 - Filed Dec 6, 1994 - NEC Corporation

4A, 4B, and 4C is called an automatic **power supply** ON-OFF method. ... and a  
voltage image (0.5 seconds) having 65 a small **transient** influence of a charge-up

...

High-voltage crowbar circuit with cascade-triggered series ignitrons

US Pat. 4232351 - Filed Jan 3, 1979 - The United States of America as represented by the United States Department of Energy

This **transient** overvoltage is reduced to to zer<sup>o</sup> - Triggering of the circuit 10

... The hot air is in connection with a **power supply**, for **testing** of multi- ...

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## Patents

Patents 1 - 3 on **transient current test pattern vector power supply fault**. (0.07 seconds)

## List view

[Cover view](#)Dynamic burn-in test equipment

US Pat. 6215324 - Filed Jan 5, 2000 - Nippon Scientific Co., Ltd.

And the difference causes **current** flows in the **test pattern** generator ...Therefore, when the currents flowing in the higher level **power supply** lines and

...

## Sort by relevance

[Sort by date \(new first\)](#)[Sort by date \(old first\)](#)Semiconductor integrated circuit fault analyzing apparatus and method therefor

US Pat. 5521516 - Filed Dec 6, 1994 - NEC Corporation

4A, 4B, and 4C is called an automatic **power supply** ON-OFF method. ... **test****pattern** from which an image is to be acquired to an entire **test vector** is

defined ...

## Any status

[Issued patents](#)[Applications](#)Integrated circuit test method and structure

US Pat. 5917331 - Filed Oct 23, 1995 - Megatest Corporation

Testing a CMOS device quiescent **power supply current** (IDDQ) is a useful ... Then, in step 304, a **test vector** is executed to bring DUT 106 to a known state. ...**Stay up to date on these results using the patents RSS feed on transient current test pattern vector power supply fault.**

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## Patents

Patents 1 - 20 on transient current test power supply fault pattern OR vector. (0.12 seconds)

## › List view

[Cover view](#)Elevated voltage level I.sub.DDQ failure testing of integrated circuits

US Pat. 5519333 - Filed Sep 9, 1994 - Sandia Corporation

The **power supply** voltage level of the device must be the same level as 50 the logic level "1" for ... is an 60 arbitrary acronym for this **transient current**

...

## › Sort by relevance

[Sort by date \(new first\)](#)[Sort by date \(old first\)](#)Integrated circuit **fault** testing system based on **power** spectrum analysis of ...

US Pat. 5949798 - Filed Feb 4, 1997 - NEC Corporation

14 illustrates conceivable measurement of a quies- repetitive **test pattern** application and the **supply current** of cent **current** 105 caused as the **supply** ...

## › Any status

[Issued patents](#)[Applications](#)Apparatus and method for defect testing of integrated circuits

US Pat. 6031386 - Filed Oct 31, 1997 - Sandia Corporation

After this, the **current** from the **power supply** will again settle down to the ... the quiescent **current**, **IDDQ**, as each **vector** in the set of **test vectors** is ...

Fast recovery **power supply**

US Pat. 4686462 - Filed Sep 26, 1985 - International Business Machines Corporation

1 illustrates in schematic form the CMOS **current** monitor **test** configuration of ... spike 17 occurs and both devices turn on producing a **transient current**, ...

Semiconductor integrated circuit **fault** analyzing apparatus and method therefor

US Pat. 5521516 - Filed Dec 6, 1994 - NEC Corporation

4A, 4B, and 4C is called an automatic **power supply** ON-OFF method. ... **test pattern** from which an image is to be acquired to an entire **test vector** is defined ...

### Dynamic burn-in test equipment

US Pat. 6215324 - Filed Jan 5, 2000 - Nippon Scientific Co., Ltd.

And the difference causes **current** flows in the **test pattern** generator ...

Therefore, when the currents flowing in the higher level **power supply** lines and

...

### Arrangement for transient-current testing of a digital electronic CMOS circuit

US Pat. 6414511 - Filed Feb 7, 2000 - Koninklijke Philips Electronics N.V.

Generally, **transient-current** measurements or so-called IDDT ... 38 that has an

importantly unsymmetric **power supply** at +30 and -5 volts, respectively, ...

### Method for fabricating integrated circuit (IC) dies with multi-layered ...

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

The quiescent **power supply current test** is a procedure which assumes a short-circuit **fault** across a plurality of signal lines in the circuit under **test** or a

...

### Integrated circuit test power supply

US Pat. 5773990 - Filed Sep 29, 1995 - Megatest Corporation

Testing a CMOS device quiescent **power supply current** (IDDQ) is a useful ...

**transient** accumulated charge, and the device under **test power supply** 102 is set

...

### Integrated circuit test method and structure

US Pat. 5917331 - Filed Oct 23, 1995 - Megatest Corporation

Testing a CMOS device quiescent **power supply current** (IDDQ) is a useful ... Then

, in step 304, a **test vector** is executed to bring DUT 106 to a known state. ...

### Test method and apparatus using energy consumption ratio

US Pat. 6513137 - Filed Oct 18, 1999 - Cardiac Pacemakers, Inc., Regents of the University of Minnesota

This method includes connecting the circuit to a BACKGROUND **power supply**, ... to the **supply** rails and measurement of the **transient vector** which maximizes NB ...

### Fail safe architecture for a computer system

US Pat. 4726024 - Filed Mar 31, 1986 - Mieczyslaw Mirowski

2E, F and G. Assuming no **fault** is found by the self-check module in step, ...

the **current** data stored in that block of RAM, writing a first **test pattern** ...

High speed I.sub.DDQ monitor circuit

US Pat. 5694063 - Filed Sep 27, 1996 - LTX Corporation

The defects DUT provides the expected output for each **test vector**. ... 1C shows the behavior of the **power supply current** functional testing may not detect ...

High resolution (quiescent) supply current system (IDD monitor)

US Pat. 6118293 - Filed May 30, 1997

More in particular a system for **supply current** testing of an electronic device or ... The overall **test** cost of a circuit depends on the **test pattern** ...

Built-in fault testing of integrated circuits

US Pat. 5332973 - Filed May 1, 1992 - The University of Manitoba

Another advantage is that the circuit will after the **transient** is expected ... circuit under **test** as well as determine whether the quiescent circuit **current** ...

Location of a faulty pulse form restorer in a cable system

US Pat. 4220833 - Filed Sep 12, 1977 - The United States of America as represented by the Secretary of the Army

Resistor 10 would be inserted in series with the entire **power supply** string. ... wherein said **power** means is a constant **current** source; wherein said **fault** ...

Ground leakage relay circuit

US Pat. 4091431 - Filed Oct 9, 1970 - Harbey Hubbell, Incorporated

Under normal conditions, the **vector** sum of the the occurrence of a voltage of ... 30 includes a dc **power supply** such a short term **transient current** flow. ...

High or low-side state relay with current limiting and operational testing

US Pat. 4631474 - Filed Jul 11, 1984 - The United States of America as represented by the Secretary of the Air Force

12 built-in **test** indications during a specified **transient** HIGH OR LOW-SIDE STATE RELAY WITH ... The switch DC **power supply**. Schmidt, Jr. in US Pat. No. ...

High speed magnetic flux sampling

US Pat. 6118284 - Filed Oct 6, 1997

Characterizing **current** transients and Ldl/dt noise in the **power/ground/clock** distribution networks within the VLSI and high-performance chip/computer ...

transient current test power supply fault pattern OR...

Photon assisted tunneling testing of passivated integrated circuits

US Pat. 4644264 - Filed Mar 29, 1986 - International Business Machines Corporation

... using the "solar-cell" the **current transient** induced in the **power supply** by

... semiconductor solar cell for **fault** by- provides an improved extraction ...

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